

**Search Notes**

Application/Control No.

10/792,297

Examiner

John P. Sheehan

Applicant(s)/Patent under  
Reexamination

SHIRAISHI ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	3/22/2007	JPS